

Application/Control No.	Applicant(s)/Patent under Reexamination
10/629,086	HAN ET AL.
Examiner	Art Unit
Tuvet Vo	2821

	SEARCHED			
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
313	402,408	11/12/2005	τv		
315	85				
362	246, 248	1	\bigvee		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
(313/402,408,407,238,477-479,313) combined with text such as electromagnetic wave shield/block/seal	11/12/2005	ΤV		
(315/85) combined with text search	11/12/2005	τv		
(362/248,246,236,227) combined with text search	11/12/2005	TV		